



7/21/2011

**PRODUCT RELIABILITY REPORT
FOR**

DS1884

Maxim Integrated Products

**4401 South Beltwood Parkway
Dallas, TX 75244-3292**

Prepared by:

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Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

DS1884

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$$

AfT = Acceleration factor due to Temperature
 tu = Time at use temperature (e.g. 55°C)
 ts = Time at stress temperature (e.g. 125°C)
 k = Boltzmann's Constant (8.617 x 10⁻⁵ eV/°K)
 Tu = Temperature at Use (°K)
 Ts = Temperature at Stress (°K)
 Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$$AfV = \exp(B * (Vs - Vu))$$

AfV = Acceleration factor due to Voltage
 Vs = Stress Voltage (e.g. 7.0 volts)
 Vu = Maximum Operating Voltage (e.g. 5.5 volts)
 B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$$Fr = X / (ts * AfV * AfT * N * 2)$$

X = Chi-Sq statistical upper limit
 N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$\text{MTTF} = 1/\text{Fr}$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE: **MTTF (YRS):** **39637** **FITS:** **2.9**
DEVICE HOURS: **702191689** **FAILS:** **1**

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **B: 0** **Tu: 25 °C** **Vu: 3.6 Volts**

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:

Process: SA E6W, 0.6um BiCMOS, 2 Poly, 2 Metal, EEPROM, 8 inch wafer
 Passivation: TEOS Oxide-Nitride Passivation
 Die Size: 106 x 146
 Number of Transistors: 26253
 Interconnect: Aluminum / 0.5% Copper
 Gate Oxide Thickness: 150 Å

ESD HBM

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	1115 DS1884 ZJ167335AA-	JESD22-A114 HBM 500 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1115 DS1884 ZJ167335AA-	JESD22-A114 HBM 1000 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1115 DS1884 ZJ167335AA-	JESD22-A114 HBM 1500 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1115 DS1884 ZJ167335AA-	JESD22-A114 HBM 2000 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1115 DS1884 ZJ167335AA-	JESD22-A114 HBM 2500 VOLTS	1	PUL'S	5	0
Total:					0	

LATCH-UP

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
LATCH-UP I	1115 DS1884 ZJ167335AA-	JESD78A, I-TEST 25C 100mA		6	0	
LATCH-UP I	1115 DS1884 ZJ167335AA-	JESD78A, I-TEST 25C 250mA		6	0	
LATCH-UP V	1115 DS1884 ZJ167335AA-	JESD78A, V-SUPPLY TEST 25C		6	0	
Total:					0	

OPERATING LIFE

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0948 DS1856	WM049367A 125C, 5.5 VOLTS	1000 HRS	77	1	40023508
HIGH TEMP OP LIFE	1035 DS18S20	FJ157931AB 125C, 5.5 VOLTS	1000 HRS	80	0	
HIGH TEMP OP LIFE	1050 DS1856	WM158219A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1050 DS1856	WM158219A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1052 DS1856	FJ162135DB 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1052 DS1856	FJ162135DB 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1052 DS1856	FJ162076CC 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1052 DS1856	FJ162076CC 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1103 DS18S20	FD162367AC 125C, 5.5 VOLTS	1000 HRS	80	0	
HIGH TEMP OP LIFE	1113 DS18S20	FD166067AB 125C, 5.5 VOLTS	384 HRS	80	0	
HIGH TEMP OP LIFE	1115 DS1884	ZJ167335AA- 125C, 3.6 VOLTS	192 HRS	77	0	
			Total:		1	

FAILURE RATE: **MTTF (YRS):** **39637** **FITS:** **2.9**
 DEVICE HOURS: **702191689** **FAILS:** **1**